

**INFORMATION DISCLOSURE
STATEMENT LIST**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/563,884
Filing Date	January 9, 2006
First Named Inventor	EICKEN <i>et al.</i>
Group Art Unit	1755
Examiner Name	Unassigned

U.S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	Document No.	Date	Name	Class	Subclass	Filing Date (if appropriate)
	A1	US 6,727,081	04/27/2004	Yang <i>et al.</i>	435	101	07/27/2001
	A2	US 6,691,783 B1	02/17/2004	Bulla <i>et al.</i>	166	294	10/25/2000
	A3	US 6,689,402 B1	02/10/2004	Nauth <i>et al.</i>	426	36	03/31/1999
	A4	US 6,685,978 B1	02/03/2004	Hauksson	426	573	04/04/2000
	A5	US 6,685,977 B1	02/03/2004	Asano <i>et al.</i>	426	565	11/09/2000
	A6	US 6,573,250 B2	06/03/2003	Umeda <i>et al.</i>	514	54	11/15/2001
	A7	US 6,605,461 B2	08/12/2003	Yamazaki <i>et al.</i>	435	252.1	07/13/2001
	A8	US 6,596,832 B2	07/22/2003	Johnston <i>et al.</i>	526	347	09/27/2002
	A9	US 6,579,714	06/17/2003	Hirabayashi <i>et al.</i>	435	292.1	02/01/2002
	A10	US 6,551,596 B2	04/22/2003	Kralovec	424	195.17	08/10/2001
	A11	US 6,511,694 B2	01/28/2003	Huang <i>et al.</i>	425	565	04/06/2001
	A12	US 6,468,442 B2	10/22/2002	Bytnar	525	70	12/19/2001
	A13	US 6,458,404 B1	10/01/2002	Adachi	426	573	05/19/1999
	A14	US 6,436,680	08/20/2002	Guezennec <i>et al.</i>	435	101	11/19/1999
	A15	US 6,436,461 B1	08/20/2002	Bouwmeesters <i>et al.</i>	426	575	06/28/1999
	A16	US 6,432,359 B1	08/13/2002	Carey <i>et al.</i>	422	63	01/18/2000
	A17	US 6,432,155 B1	08/13/2002	Swazey <i>et al.</i>	71	27	08/11/2000
	A18	US 6,423,359 B1	07/23/2002	Braverman	426	565	02/16/2000
	A19	US 6,416,978	07/09/2002	Lee <i>et al.</i>	435	101	10/27/2000
	A20	US 6,344,346 B1	02/05/2002	Alami <i>et al.</i>	435	101	02/22/2000
	A21	US 6,299,915 B1	10/09/2001	Nussinovitch <i>et al.</i>	426	89	03/09/2001
	A22	US 6,126,850	10/03/2000	Ishioka <i>et al.</i>	252	70	10/06/1998
	A23	US 6,027,925	02/22/2000	Pollock <i>et al.</i>	435	104	06/12/1998
	A24	US 5,863,973	01/26/1999	Carder <i>et al.</i>	524	388	09/26/1997
	A25	US 5,772,912	06/30/1998	Lockyer <i>et al.</i>	252	70	01/24/1996
	A26	US 5,514,791	05/07/1996	Doherty <i>et al.</i>	536	114	04/25/1994
	A27	US 5,444,160	08/22/1995	Day <i>et al.</i>	536	3	04/26/1994
	A28	US 5,321,133	06/14/1994	Collicet <i>et al.</i>	536	118	01/16/1992
	A29	US 5,089,481	02/18/1992	Muto <i>et al.</i>	514	54	11/15/1990
	A30	US 5,079,036	01/07/1992	Roe <i>et al.</i>	427	212	07/27/1990
	A31	US 4,713,449	12/15/1987	Vanderslice <i>et al.</i>	536	123	08/06/1985

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Examiner's Initials	Cite No.	Document No.	Date	Name	Class	Subclass	Filing Date (if appropriate)
	A32	US 4,698,172	10/06/1987	Tye <i>et al.</i>	252	70	08/04/1986
	A33	US 4,426,409	01/17/1984	Roe	427	221	07/02/1982
	A34	US 4,287,236	09/01/1981	Kestner <i>et al.</i>	427	221	08/10/1979
	A35	US 3,659,026	04/25/1972	Schuppner	424	361	12/08/1969
	A36	US 3,054,689	09/18/1962	Jeanes <i>et al.</i>	106	208	10/31/1960
	A37	US 3,000,790	09/19/1961	Jeanes <i>et al.</i>	195	31	12/30/1959
	A38	US RE38,385 E	01/13/2004	Franks <i>et al.</i>	514	54	08/28/2001
	A39	US 4,117,214	09/26/1978	Parks <i>et al.</i>	427	220	11/28/1977
	A40	US 4,388,203	06/14/1983	Nimerick <i>et al.</i>	252	70	11/20/1981
	A41	US 6,183,664	02/06/2001	Kim <i>et al.</i>	252	70	10/22/1999
	A42	US 4,358,389	11/09/1982	Konig-Lumer <i>et al.</i>	252	70	03/18/1981
	A43	US 4,439,337	03/27/1984	Nimerick <i>et al.</i>	252	70	11/20/1981
	A44	US 5,261,241	11/16/1993	Kitahara <i>et al.</i>	62	4	01/29/1992
	A45	US 6,180,562	1/30/2001	Blum	504	117	1/20/1999
	A46	US 6,368,591	04/09/2002	Chen <i>et al.</i>	424	93	5/15/1998

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	A47	EP 0 437 360 A1	07/17/1991	Warner-Lambert Company	
	A48	JP 05-328859	12/14/1993	ZH NAGANO-KEN NOKYO CHIIKI KAIHATSU KIKO	

NON PATENT LITERATURE DOCUMENTS

Examiner's Initials	Cite No.	Non-Patent Citations (include Author, Title, Publisher, Relevant Pages, Date and Place of Publication)
	A49	Cox, G. F. N. and Weeks, W. F. Numerical simulations of the profile properties of undeformed first-year sea ice during the growth season. J. Geophys. Res., 93:12449-12460 (1988)
	A50	Cox, G. F. N. and Weeks, W. F. Equations for determining the gas and brine volumes in sea-ice samples. J. Glaciol., 29:306-316 (1983)
	A51	Cox, G. F. N. and Weeks, W. F. Brine drainage and initial salt entrapment in sodium chloride ice. CRREL Res. Rep., 345 (1975)
	A52	Eicken, H. From the microscopic to the macroscopic to the regional scale: Growth, microstructure and properties of sea ice. In: Thomas, D. N. and Dieckmann, G. S. Sea ice - An introduction to its physics, biology, chemistry and geology. London: Blackwells Scientific Ltd., 22-81 (2003)

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Examiner's Initials	Cite No.	Non-Patent Citations (include Author, Title, Publisher, Relevant Pages, Date and Place of Publication)
	A53	Eicken, H. Deriving modes and rates of ice growth in the Weddell Sea. AGU Antarct. Res. Ser. (Antarctic Sea Ice Physical Processes, Interactions and Variability, Edited by M. O. Jeffries). 74:89-122 (1998)
	A54	Groisman, A. and Steinberg, V. Efficient mixing at low Reynolds numbers using polymer additives. Nature, 410:905-908 (2001)
	A55	Igoe, R. S. Hydrocolloid interactions useful in food systems. Food-Technol. Chicago, Institute of Food Technologists. Apr 1982; 36:4:72-74.
	A56	Izutsu, K.-I.; Yoshioka, S., and Kojima, S. Effect of cryoprotectants on the eutectic crystallization of NaCl in frozen solutions studied by differential scanning calorimetry (DSC) and broad-line pulsed NMR. Chem. Pharm. Bull. 1995; 43(10):1804-1806
	A57	Marcotte, M., Taherian Hoshahili, A. R., and Ramaswamy H.S. Rheological properties of selected hydrocolloids as a function of concentration and temperature. Food Res. Inter. 2001; 34:695-703
	A58	Miyawaki, O.; Liu, L., and Nakamura, K. Effective partition constant of solute between ice and liquid phases in progressive freeze-concentration. J. Food Sci. 1998; 63(5):756-758.
	A59	Paul, J. Binary ice - Technologies for the production of pumpable ice slurries. Proc. Inst. Refrigeration. 1993; 1992-93:5-1-10.
	A60	Smedsrud <i>et al.</i> , "Sea Ice Formation on a Very Cold Surface," <i>Geophysical Research Letters</i> , 30(6):1284, pp. 17-1 - 17-4 (2003)
	A61	Spencer, R. J.; Moller, N., and Weare, J. H. The prediction of mineral solubilities in natural waters: A chemical equilibrium model for the Na-K-Ca-Mg-Cl-504-H2O system at temperatures below 25 °C. Geochim. Cosmochim. Acta. 1990; 54:575-590.
	A62	Weeks, W. F. and Ackley, S. F. The growth, structure and properties of sea ice. Untersteiner, N. Dordrecht (NATO ASI B 146): Martinus Nijhoff Publ.; 1986: 9-164.
	A63	Wettlaufer, J. Introduction to crystallization phenomena in natural and artificial sea ice. Lepparanta, M. Helsinki: Helsinki University Press, 105-194 (1998)

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